

Using the Atomic Force Microscope to Measure Roughness Characteristics of Acetabular Prosthetic Shells Used as Hip Socket Replacements

Shilest Jani*, Gary Williams, Dr. Silvio P. Marchese-Ragona and Briggs Christie; TopoMetrix, *Smith and Nephew Richards, Memphis, TN

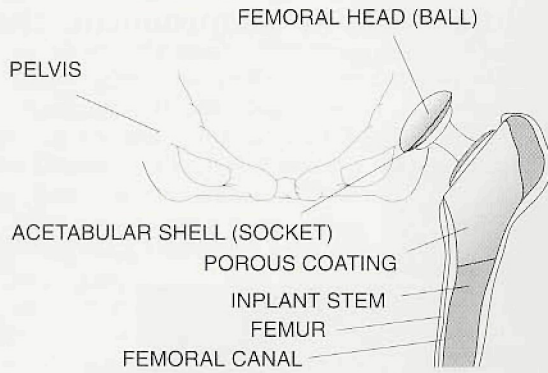


Figure 1. Hip Socket Replacement

Total replacement of a diseased or traumatized hip joint is fast becoming one of the most common surgical procedures. The acetabular prosthetic shell is gaining widespread acceptance as a socket replacement for this procedure. Bio-materials research is providing a wealth of information regarding the life span, wear characteristics, and performance of these replacements, with a major clinical finding being the destruction of bone (osteolysis) at interfaces with the implants. Osteolysis is widely thought to be associated with the particulate wear debris released from articulation of the ball and socket. Formation and release of these particulates will depend not only on the relative motion occurring but also on the surface roughness of the replacement materials.

In this study we used the Atomic Force Microscope (AFM) to compare the internal surface topography of two acetabular shells, one polished to a mirror finish and the other unpolished (Figure 2). The ultimate goal of the study was to determine whether a polished shell reduces the amount of wear and tear on the ultra-high molecular weight polyethylene (UHMWPE) insert that is fitted between the shell and the Femoral ball (Figure 1).

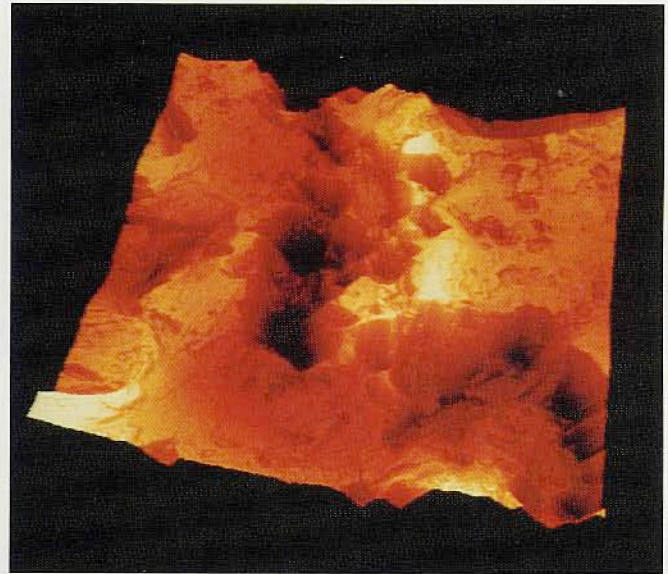


Figure 2. 3-dimensional AFM image of unpolished prosthetic hip replacement.
Sample courtesy of BioMet.

The Femoral ball, constructed of either Cobalt-chrome or ceramic, replaces the worn head of the thigh bone and fits into a UHMWPE cup, which replaces the socket. The UHMWPE sleeve fits snugly into the acetabular shell, but experiences friction and abrasion due to the torsion and impact of movement by the human body. Billions of particles of the polyethylene and shell surfaces may be released into the socket area, collecting around the hip to cause potential abrasion and bone loss.

The two types of prosthetic joints used in our comparison were unused Ti 6Al 4v; one was polished and the other was not. As the measurement of nanometer scale roughness characteristics realize increasing importance in the life sciences, the Atomic Force Microscope (AFM) is providing 3-dimensional data, analysis, and imaging capabilities to researchers. The AFM benefits the analysis in the following areas:

- The AFM can accurately measure in 3 dimensions with nanometer resolution
- AFM imaging may be performed in ambient room conditions.
- Analysis software tools are used to acquire and present quantitative information.
- Concave or large surface areas may be sampled and imaged without damage.
- High aspect ratio probes measure height dimension accurately.

Concave surfaces have been difficult to investigate by AFM because of probe geometrics. To overcome this obstacle, a plastic replica was produced (Figure 3) by depositing a drop of liquid nitrocellulose replicating material onto a small area of the clean concave surface of each acetabular shell. Once dry, double-sided tape was gently pressed onto the now solid replica, pulled away from the surface, and placed onto an AFM sample holder.

A high aspect ratio SuperTip™ (10:1 typical) was used to scan both samples at 500 x 500 pixels. Figure 4 shows the line profile of the replica from the unpolished shell and compares the replica line profile from the polished shell (Figure 5) by scaling both to the greater topography of the roughness sample (2957 nm).

- Continued on Page 16

MICRO VISION ONE

A five-day intensive course in Light Microscopy. Intended for practitioners and new users in clinical, chemical, forensic, materials and biological sciences. The blend of lectures and hands-on exercises emphasizes microscopical technique and strategies for problem solving.

June 19-23, 1995
Technical Education Center Osceola
Kissimmee, Florida

Tuition: \$600
3.5 Continuing Education Units

Principal Instructors:

Dr. Barry G. Fookes: *International consultant in microscopy and former Director, Experimental Techniques Center, Brunel University, U.K.*

Ms. Barbara Foster: *President, Microscopy/Marketing & Education.*

For further details and registration forms, contact:

Gordon Grau Scientific
901-G Rachna Lane
Kissimmee, FL 34741
Tel./Fax: (407)931-1975

Using the Atomic Force Microscope to Measure Roughness Characteristics of Acetabular prosthetic Shells Used as Hip Socket Replacements

(Continued from Page 14)

Figures 4 and 5 also compare topographic views of the surface and quantitative roughness values to numerically characterize the unused surfaces of the differing acetabular prosthetic shells. The unpolished surface measures a total area height dimension of 2918.54 nm compared to only 134.71 nm for the polished surface. Single line roughness measurements and Ra values (average departure from a mean line) from both surfaces also illustrate these differences. AFM examination of similar surfaces after they are removed from service are expected to reveal further information regarding material deterioration.

It is hoped that the quantitative data from these experiments may establish a basis of study that will improve future prosthetic device performance and ensure the highest quality of life for their recipients. ■

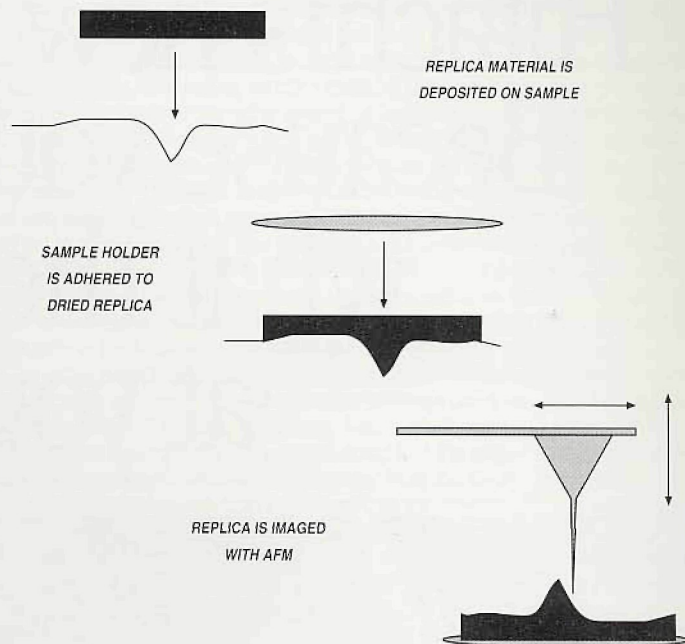
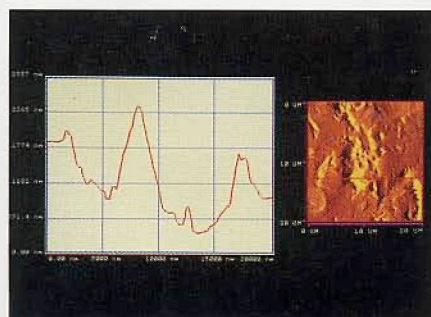


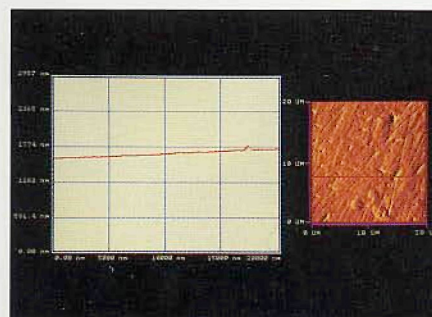
Figure 3. Use of replica for AFM imaging.



Area Roughness
 Ra 337.37 nm
 RMS 429.86 nm
 Z Avg. 1755.73 nm
 Z Max 2918.54 nm

Line Roughness
 Ra 464.86 nm
 Rp 864.13 nm
 Rpm 499.95 nm
 Rt 2294.62 nm
 Rtm 1407.32 nm

Figure 4. Unpolished shell line profile, topographic view and roughness values



Area Roughness
 Ra 7.51 nm
 RMS 10.33 nm
 Z Avg. 36.74 nm
 Z Max 134.71 nm

Line Roughness
 Ra 10.59 nm
 Rp 97.90 nm
 Rpm 34.48 nm
 Rt 133.42 nm
 Rtm 51.18 nm

Figure 5. Polished shell line profile, topographic view and roughness values

For your Electron Microscopy Laboratory:

MICRO STAR DIAMOND KNIVES

★ **BEST QUALITY**
 Backed by an iron clad guarantee: You don't pay until you have tested your knife and are totally satisfied with its flawless quality.

★ **BEST SELECTION**
 8 boat styles, 15 types and 59 sizes, from 1 to 10mm.

★ **BEST SERVICES**
 Exchange (or resharpen) your old knife, any brand, type, size or age for a new MICRO STAR at the resharpening price.

800 533 2509 FAX: 409 294 9861 E-MAIL: US3SNQ7N@IBMMAIL.COM

EDS to fit your Budget!

Choose basic acquisition, fully quantitative or standardless analysis on either a Macintosh or IBM platform. Use your existing detector and pulse processor or buy a new complete system from us.

DAPPLE SYSTEMS

355 W. Olive Ave., Suite 100
 Sunnyvale, CA 94086
 Tel: (408) 733-3283
 Fax: (408) 736-2350

New WinEDS Version 2.0 includes full quantitative analysis software for Microsoft Windows™ 3.1

Featuring . . .

- ⇒ ZAF OR PRZ MATRIX CORRECTION
- ⇒ AUTOMATIC ANALYSIS SETUP
- ⇒ FAST!!! - 10 ELEMENT ANALYSIS UNDER 0.5 SEC
- ⇒ CUT AND PASTE RESULTS INTO YOUR FAVORITE WINDOWS™ WORD PROCESSOR

Quantitative results can be quickly printed or pasted into your favourite Word Processor.

WinEDS version 2.0, the latest upgrade of the affordable PC analysis system for Microsoft Windows™ 3.1 now includes full quantitative analysis. Choose from ZAF or PRZ matrix corrections. Our exclusive WinEDS Automatic Analysis Setup intelligently configures analysis parameters according to the elements identified. Quantitative results are only a few quick mouse clicks away! WinEDS will even automatically determine common oxide formulas for mineral analysis. WinEDS Version 2.0 also features the fastest spectral scrolling in its class, vastly superior to most so called mainframe analysers.

WinEDS

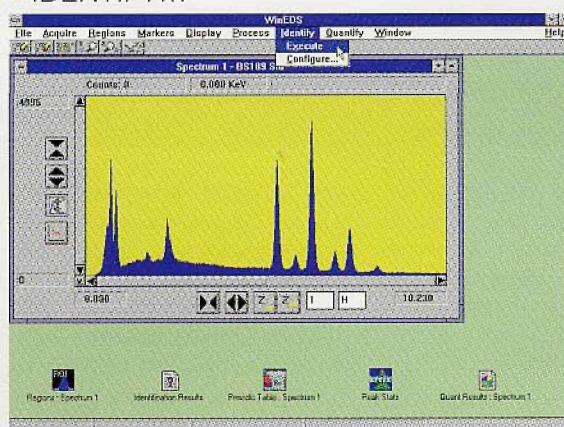
VERSION 2.0
HIGH PERFORMANCE XRAY MICROANALYSIS

THOMSON SCIENTIFIC INSTRUMENTS PTY LTD
216 DRUMMOND STREET, CARLTON, 3053, VICTORIA, AUSTRALIA.
TELEPHONE: (03) 9663 2738 FAX: (03) 9663 3680

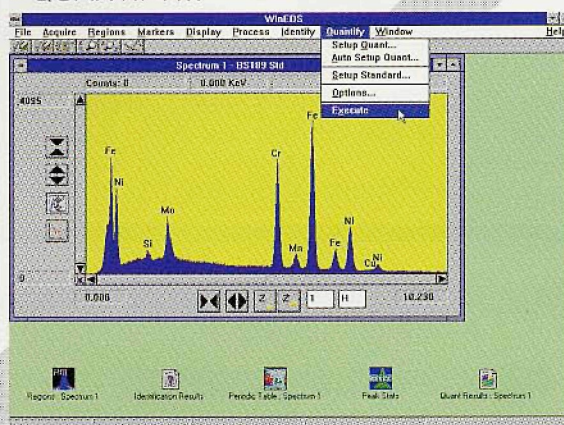
ACQUIRE...



IDENTIFY...



QUANTIFY...



PRINT...

Line	element	atomic	stddev	matrix	wt	atom	ovch
SiKα	EDS	0.0018	0.0002	1.4930	0.0039	0.98	0.15
CaKα	EDS	0.2209	0.0107	0.9192	0.2025	2.21	2.61
MnKα	EDS	0.0036	0.0010	0.9823	0.0021	0.12	2.30
FeKα	EDS	0.4933	0.0162	0.9520	0.4664	4.94	2.91
NiKα	EDS	0.3600	0.0060	0.7802	0.2268	2.31	1.69
CuKα	EDS	0.0036	0.0011	1.9730	0.0039	0.03	1.87
NiLα	EDS	0.2634	0.0014	1.2773	0.0682	0.40	6.96

total					1.0029		

comp	wt%	SD%	norm%				
Si	0.39	0.94	0.99				
Cr	20.25	0.34	30.15				
Fe	3.21	1.33	0.32				
Mn	45.64	0.51	45.35				
Ni	23.86	0.70	23.72				
Cu	0.39	0.53	0.39				
Mn	6.42	0.16	6.70				
total	100.69		100.00				

USA AGENT
EVEX ANALYTICAL INSTRUMENTS INC.
PRINCETON, NJ (908) 874-3800 FAX (908) 874 4647

